

<b>Notice of References Cited</b>	Application/Control No. 10/611,308	Applicant(s)/Patent Under Reexamination WU ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,671,116	12-2003	Akagi et al.	360/55
	C	US-4,210,946	07-1980	Iwasaki et al.	360/131
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	K	US-			
	L	US-			
	M	US-			

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	EPO Abstract of Japan of JP 08-007250-A (Pub. Num: 08007250)
	V	Machine Translation of JP 08-007250-A
	W	Derwent Abstract Translation of JP 55-091105-A (Der. Acc. No. 1980-59620C)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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